



3080K

N-Channel Trench Power MOSFET

Features

30V,80A

$R_{DS(ON)}=3.4\text{m}\Omega$ (Typ.) @ $V_{GS}=10\text{V}$

$R_{DS(ON)}=5.7\text{m}\Omega$ (Typ.) @ $V_{GS}=4.5\text{V}$

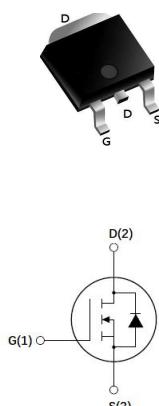
Advanced Trench Technology

Provide Excellent $R_{DS(ON)}$ and Low Gate Charge

Application

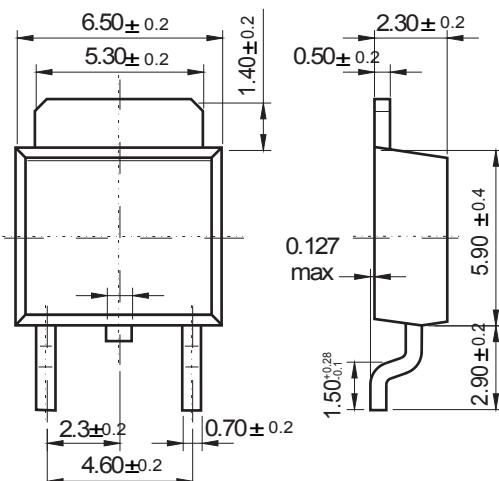
Load Switch

PWM Application



TO-252

Unit: mm



Dimensions in inches and (millimeters)

Absolute Maximum Ratings ($T_c=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_c = 25^\circ\text{C}$	80	A
		$T_c = 100^\circ\text{C}$	62	A
I_{DM}	Pulsed Drain Current ^{note1}		300	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		210	mJ
P_D	Power Dissipation	$T_c = 25^\circ\text{C}$	81	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.87	$^\circ\text{C}/\text{W}$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +175	$^\circ\text{C}$

3080K

Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V},$	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0	1.6	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$	-	3.4	7	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$	-	5.7	9	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=15\text{A}$	-	26	-	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=15\text{V}, V_{GS}=0\text{V}, f=1.0\text{MHz}$	-	2153	-	pF
C_{oss}	Output Capacitance		-	327	-	pF
C_{rss}	Reverse Transfer Capacitance		-	287	-	pF
Q_g	Total Gate Charge	$V_{DS}=25\text{V}, I_D=30\text{A}, V_{GS}=10\text{V}$	-	45	-	nC
Q_{gs}	Gate-Source Charge		-	3	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	15	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=15\text{V}, I_D=30\text{A}, R_{\text{GEN}}=3\Omega, V_{GS}=10\text{V}$	-	21	-	ns
t_r	Turn-on Rise Time		-	32	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	59	-	ns
t_f	Turn-off Fall Time		-	34	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	80	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	300	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}, I_s=30\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	15	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	4	-	nC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J=25^\circ\text{C}, VDD=30\text{V}, VG=10\text{V}, RG=25\Omega, L=0.5\text{mH}$

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

RATING AND CHARACTERISTIC CURVES (3080K)

Figure 1: Output Characteristics

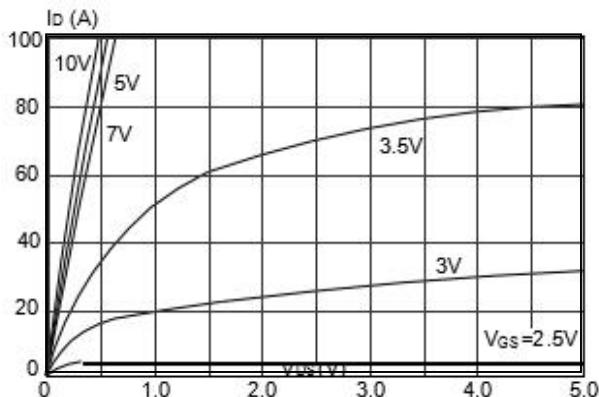


Figure 2: Typical Transfer Characteristics

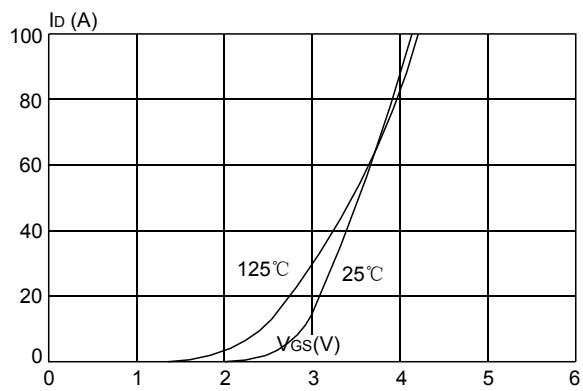


Figure 3: On-resistance vs. Drain Current

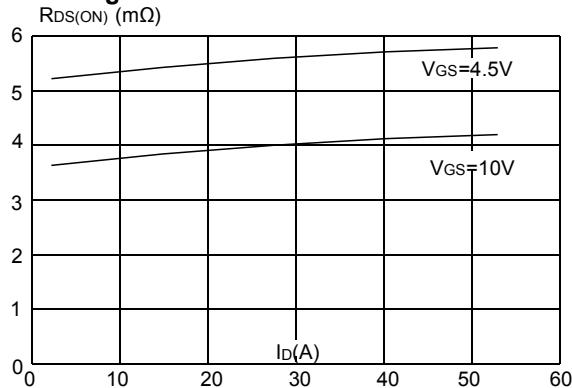


Figure 4: Body Diode Characteristics

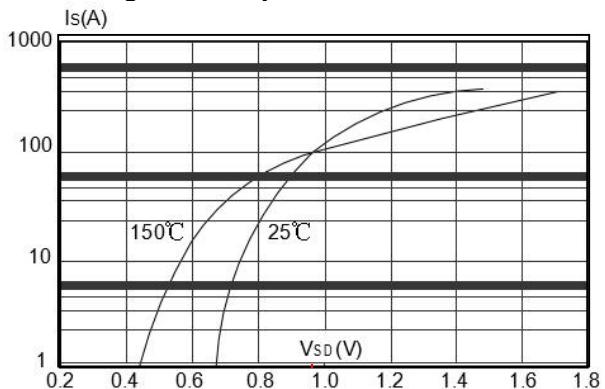


Figure 5: Gate Charge Characteristics

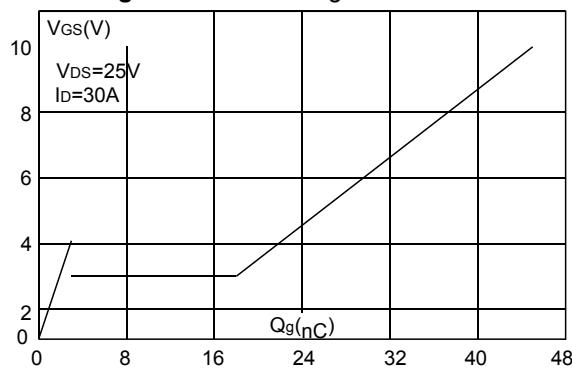
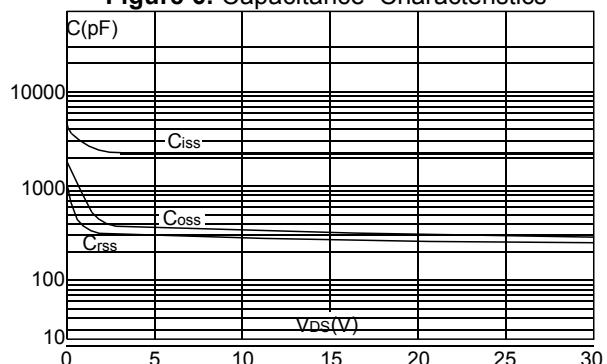


Figure 6: Capacitance Characteristics



RATING AND CHARACTERISTIC CURVES (3080K)

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

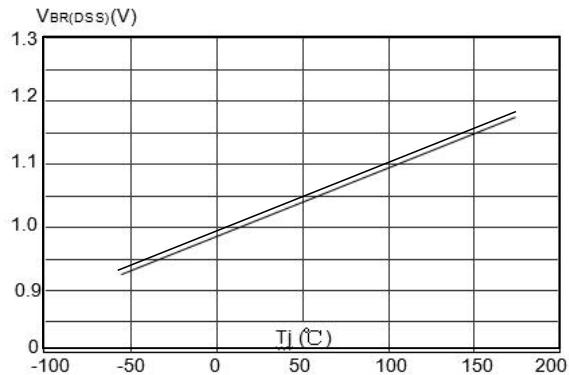


Figure 9: Maximum Safe Operating Area

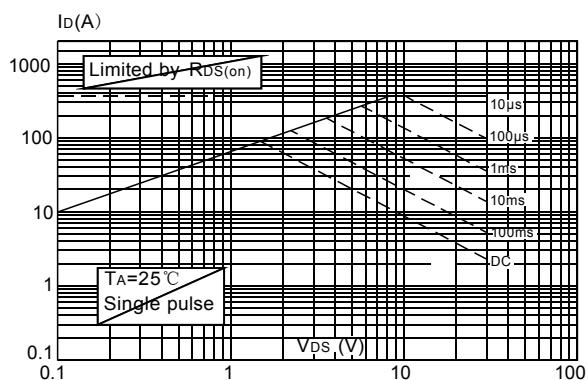


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-252)

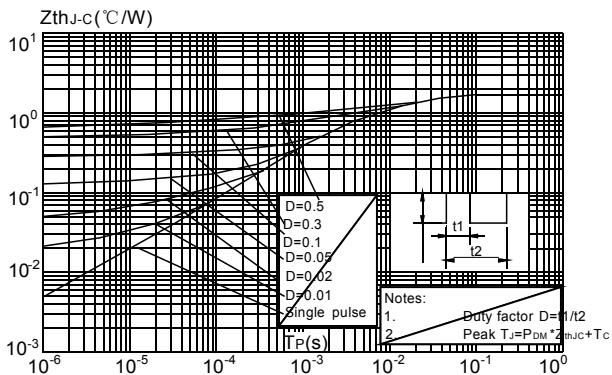


Figure 8: Normalized on Resistance vs. Junction Temperature

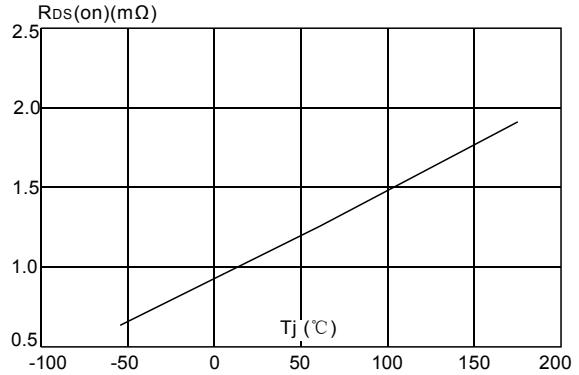
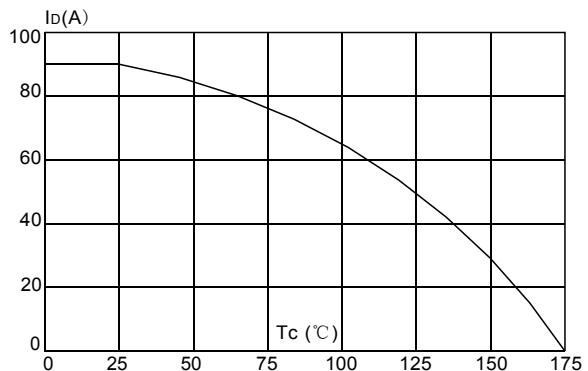


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



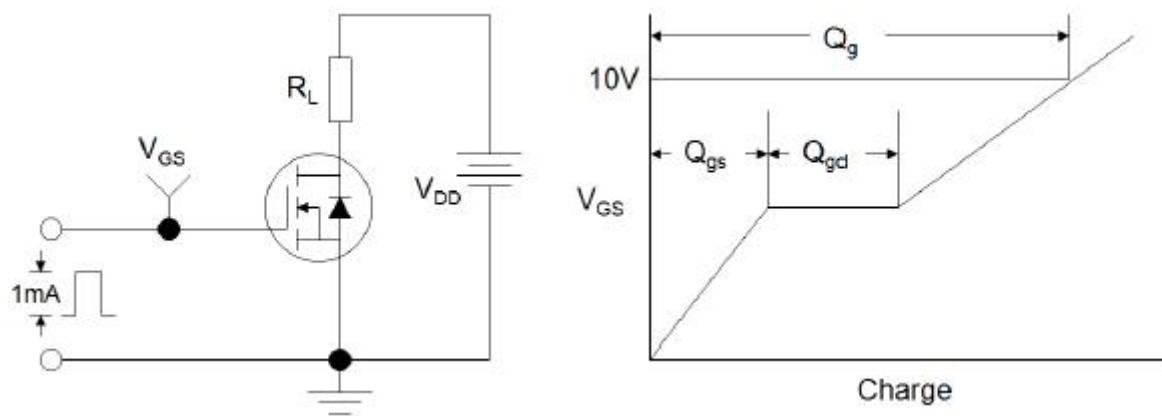


Figure 1: Gate Charge Test Circuit & Waveform

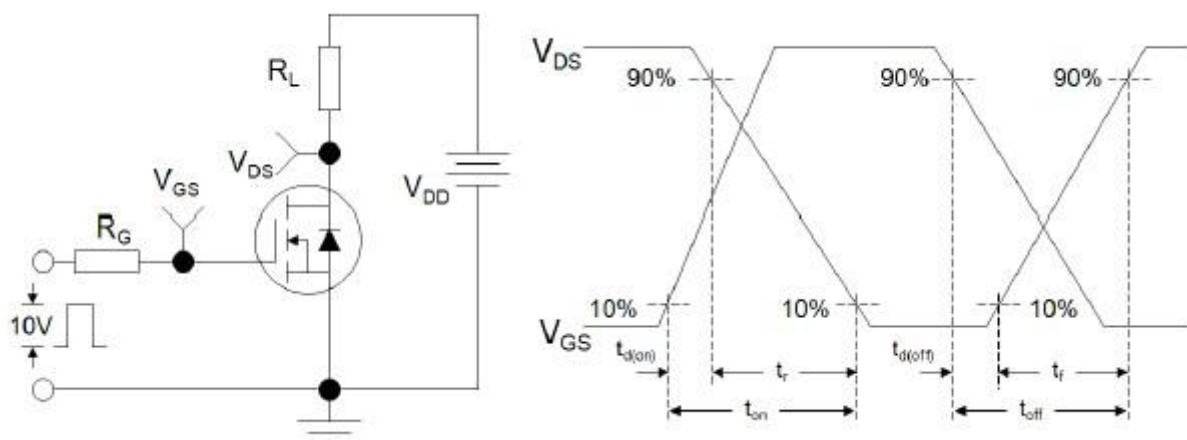


Figure 2: Resistive Switching Test Circuit & Waveforms

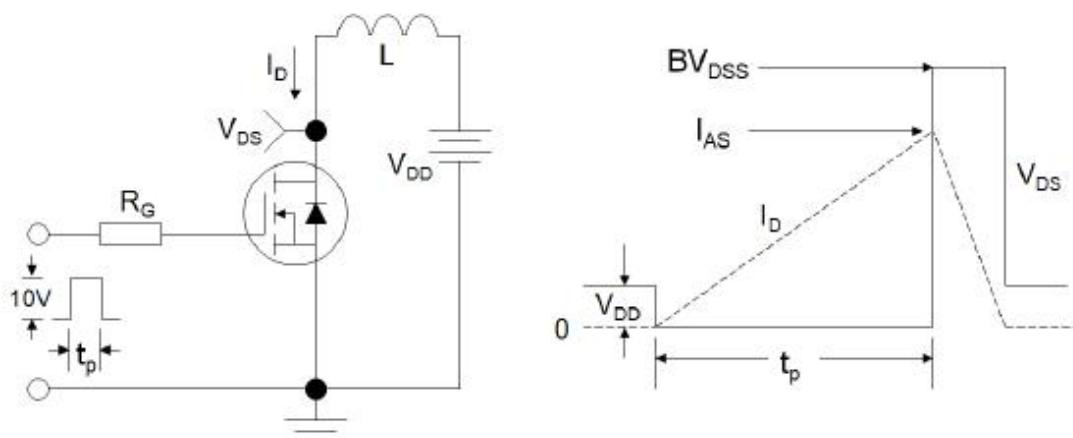
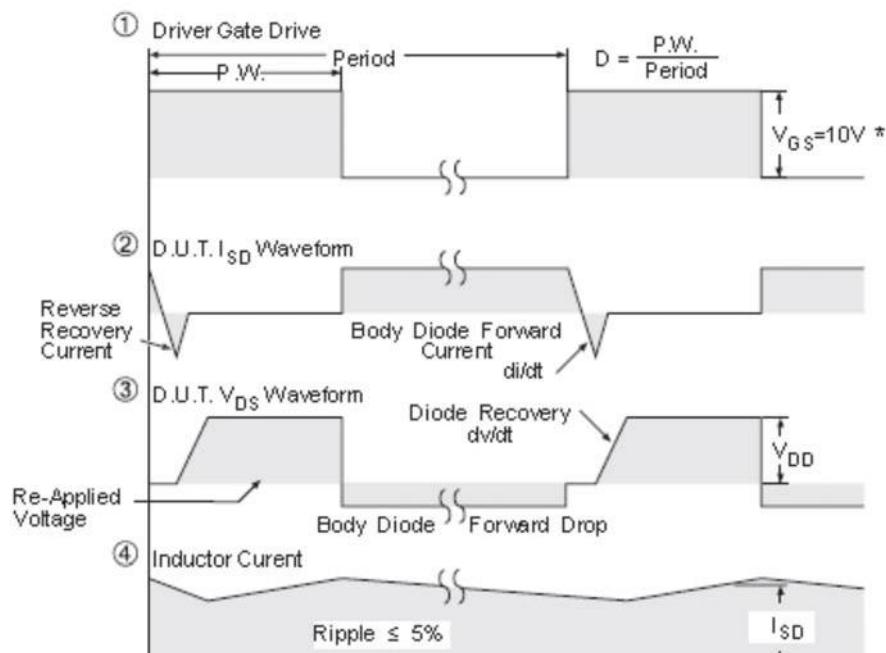
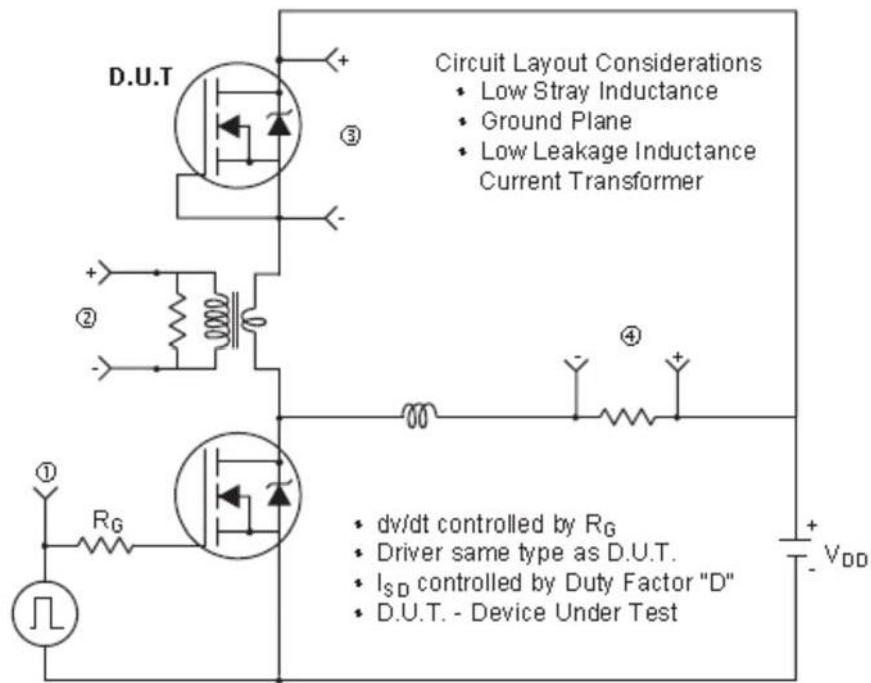


Figure 3: Unclamped Inductive Switching Test Circuit & Waveforms



* $V_{GS} = 5V$ for Logic Level Devices

Figure 4:Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)